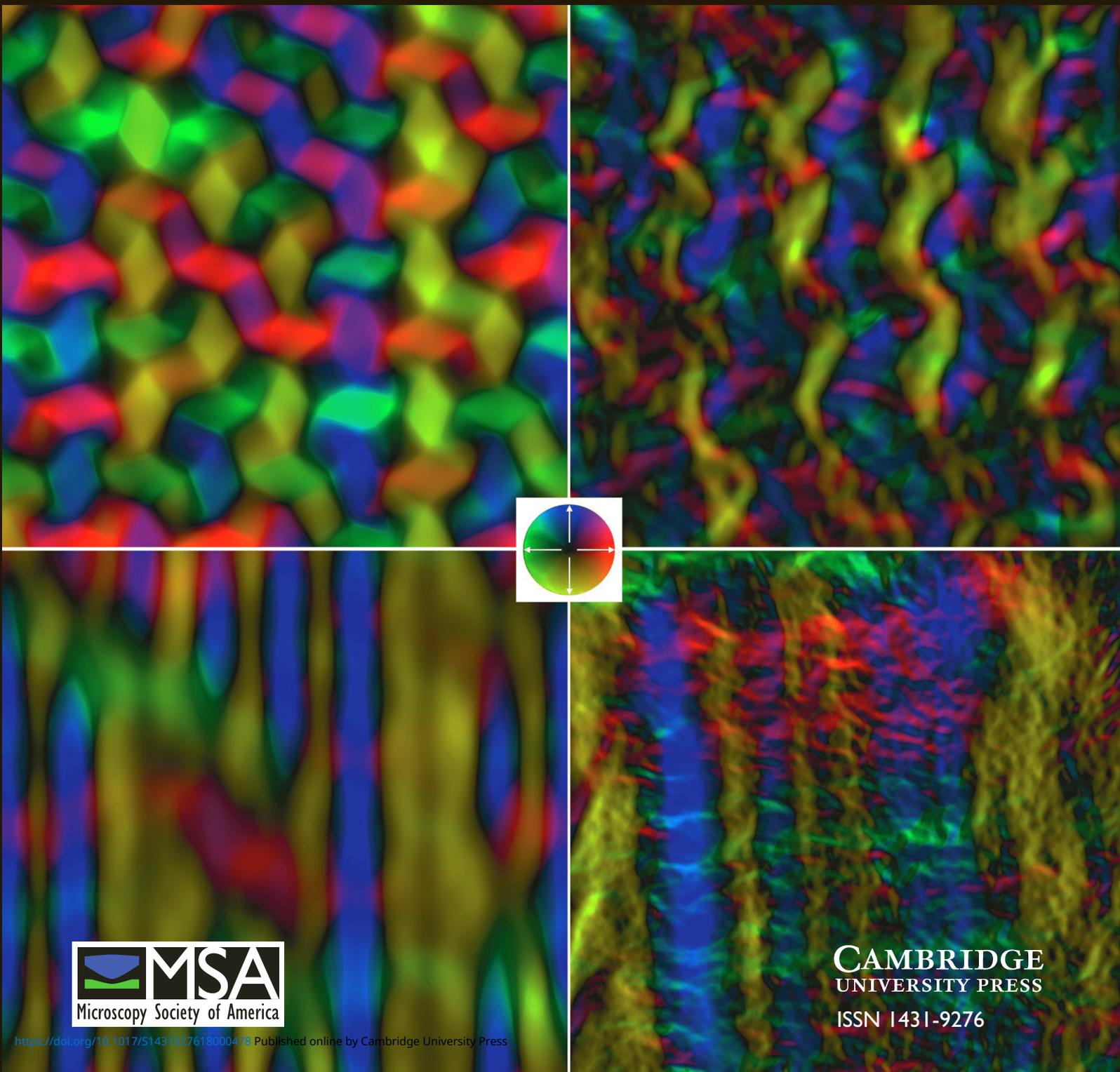


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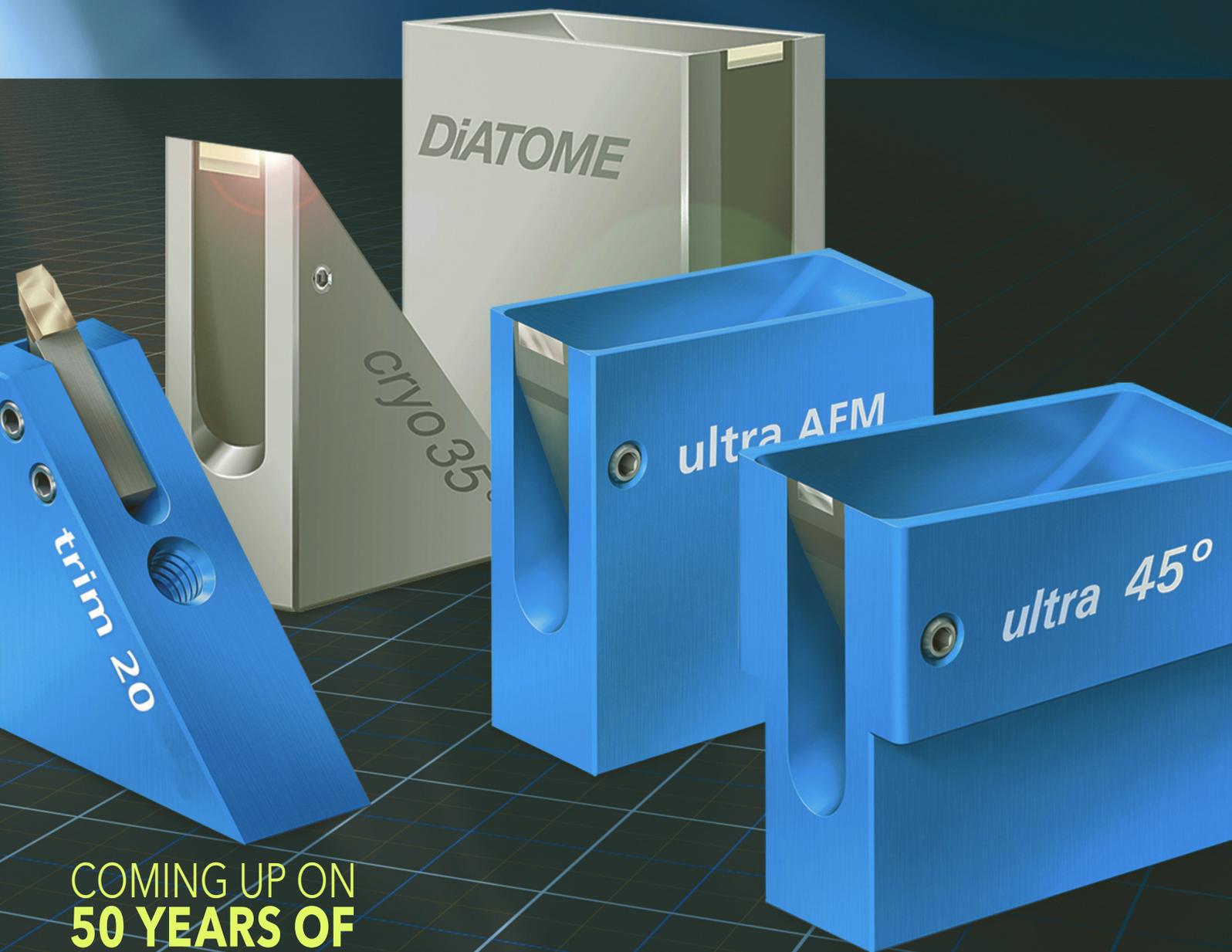
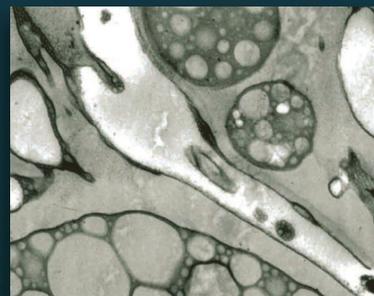
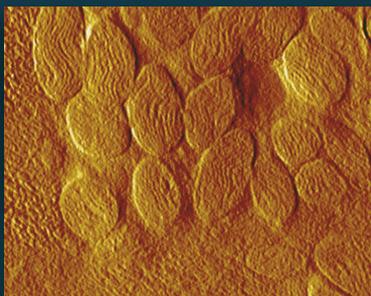
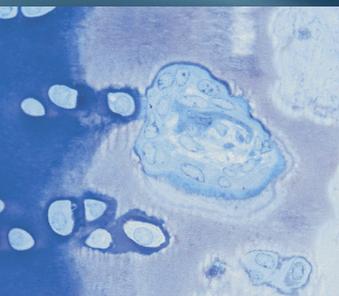


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Materials and Condensed Matter Physics
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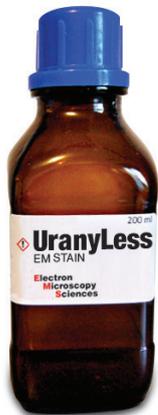
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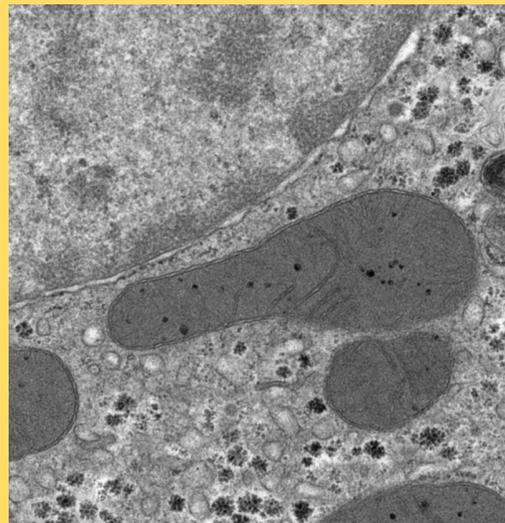
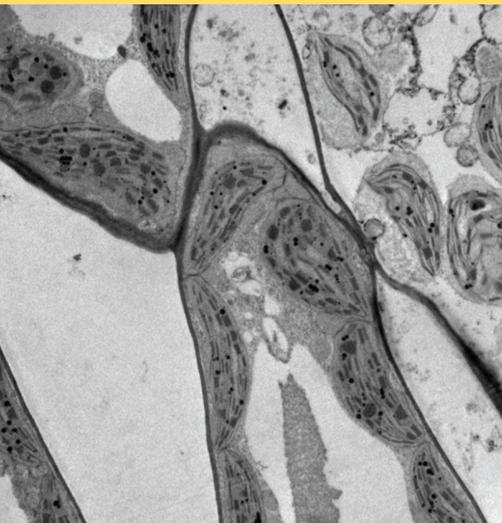
Room Temperature

pH

6.8

Disposal

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References

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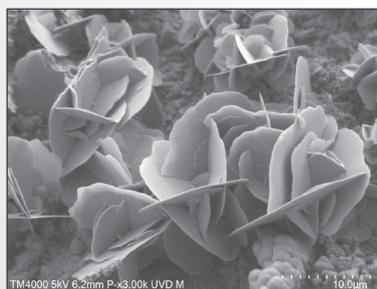
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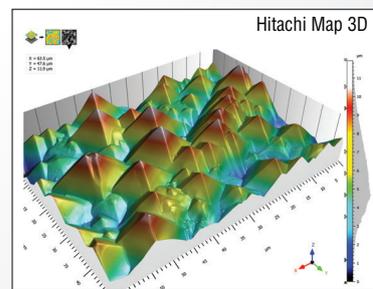
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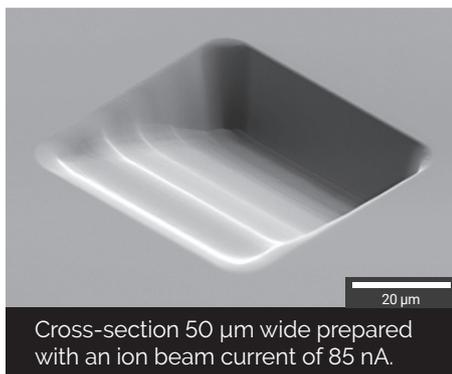
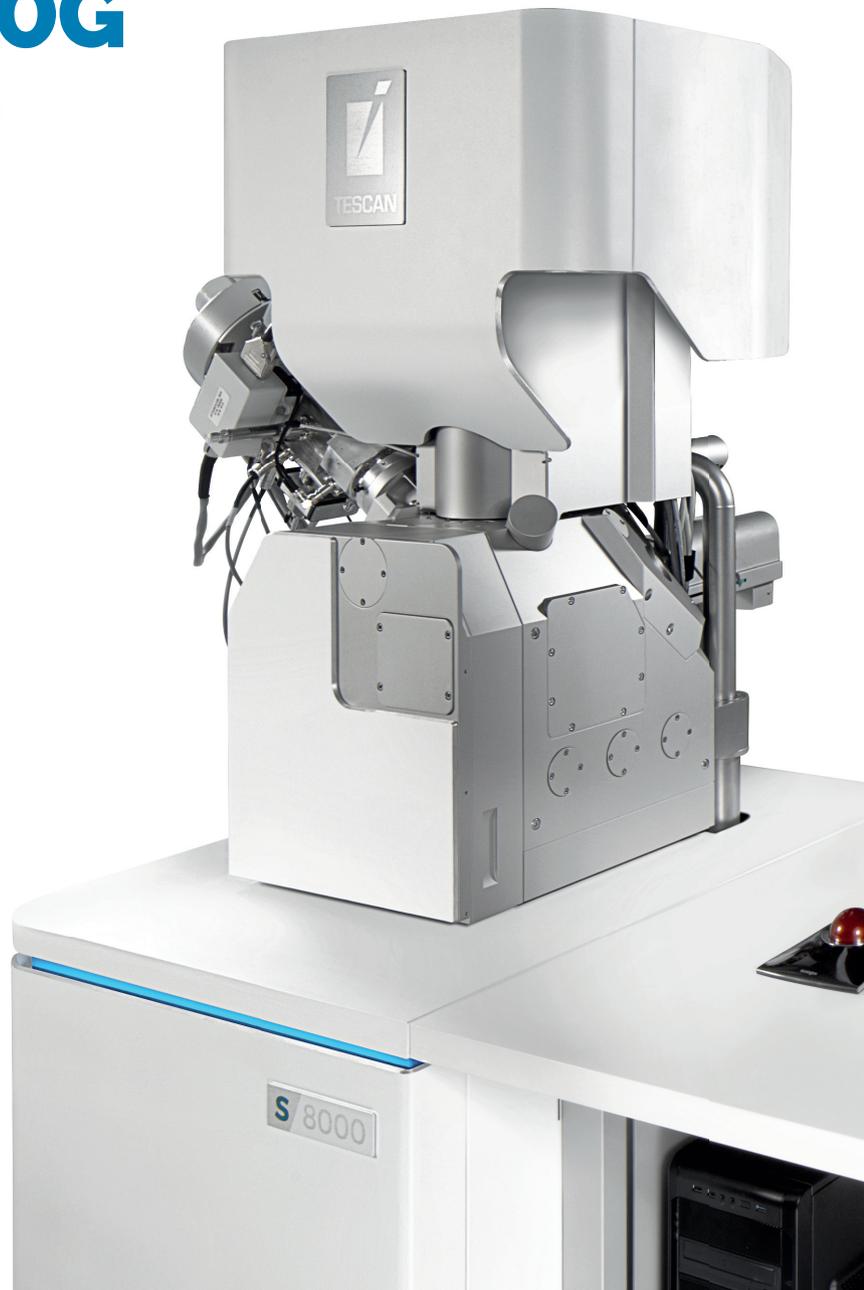
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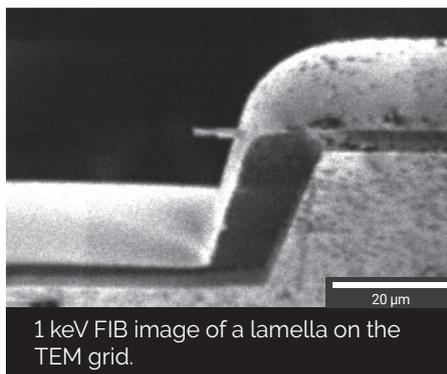
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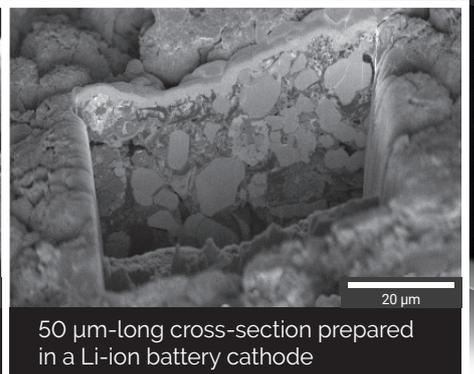
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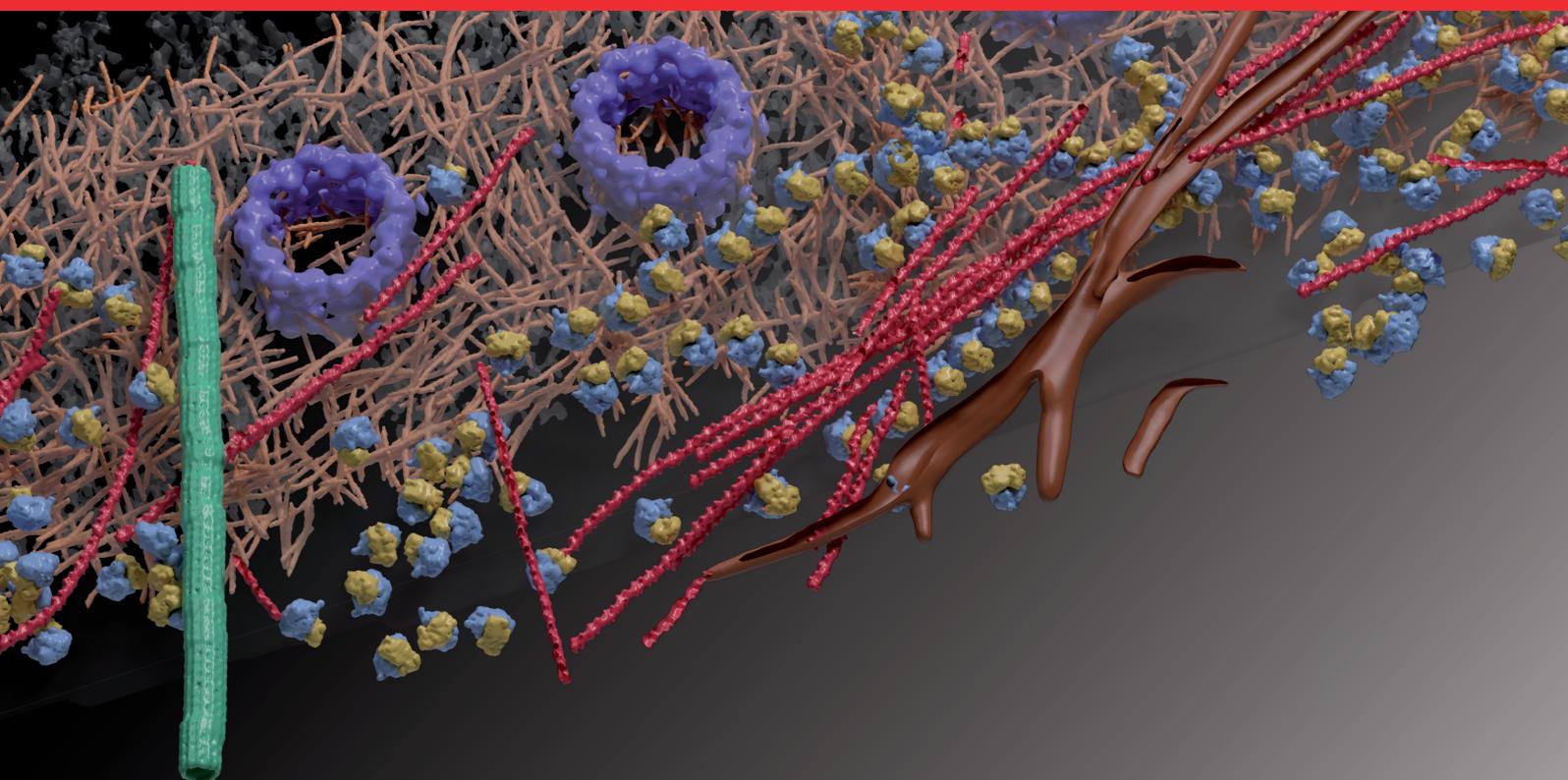
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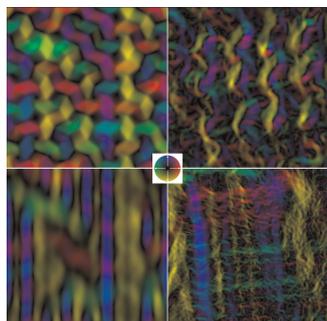
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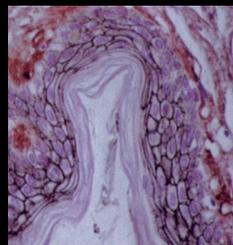
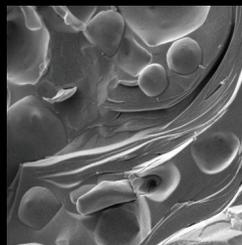
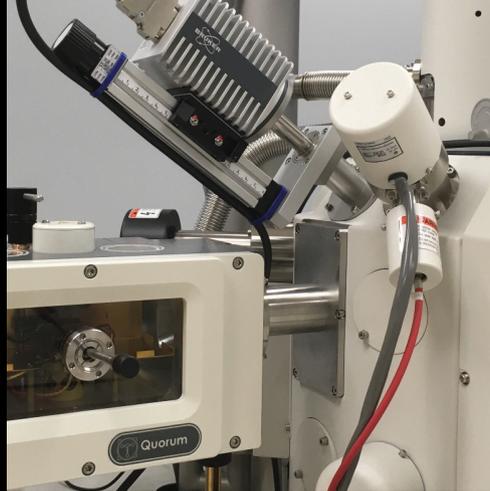
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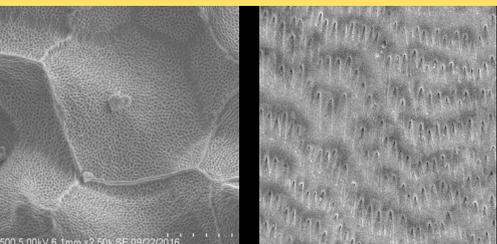
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